

FDD6690A

N-Channel, Logic Level, PowerTrench™ MOSFET

General Description

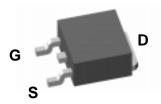
This N-Channel Logic level MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on state resistance and yet maintain low gate charge for superior switching performance.

Applications

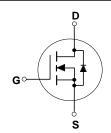
- DC/DC converter
- Motor drives

Features

- 46 A, 30 V. $R_{DS(ON)} = 0.012~\Omega~$ @ $V_{GS} = 10~V$ $R_{DS(ON)} = 0.016~\Omega~$ @ $V_{GS} = 4.5~V.$
- Low gate charge (17nC typical).
- Fast switching speed.
- $\bullet \;\;$ High performance trench technology for extremely low $R_{\text{DS(ON)}}.$



TO-252



Absolute Maximum Ratings T _A =25°C unless otherwise noted				
Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		30	V
V_{GSS}	Gate-Source Voltage		<u>+</u> 20	V
I _D	Drain Current - Continuous	(Note 1)	46	Α
		(Note 1a)	12	
	Drain Current - Pulsed		100	
P _D	Maximum Power Dissipation @ T _C = 25°C	(Note 1)	50	W
	T _A = 25°C	(Note 1a)	2.8	
	T _A = 25°C	(Note 1b)	1.3	
T _J , T _{stg}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics				
$R_{ heta JC}$	Thermal Resistance, Junction-to-Case	(Note 1a)	2.5	°C/W
$R_{\theta^{JA}}$	Thermal Resistance, Junction-to-Ambient	(Note 1b)	96	°C/W

Package Marking and Ordering Information					
Device Marking	Device	Reel Size	Tape width	Quantity	
FDD6690A	FDD6690A	13"	16mm	2500	

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-Sou	Irce Avalanche Ratings (Note	1)				
W _{DSS}	Single Pulse Drain-Source Avalanche Energy	$V_{DD} = 15 \text{ V}, I_D = 46 \text{ A}$			150	mJ
I _{AR}	Maximum Drain-Source Avalanche C	Current			46	Α
Off Chara	cteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	30			V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$, Referenced to $25^{\circ}C$		25		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, V_{GS} = 0 \text{ V}$			1	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 20V, V_{DS} = 0 V$			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
	cteristics (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, \ I_D = 250 \ \mu A$	1	1.6	3	V
$rac{\Delta {\sf V}_{\sf GS(th)}}{\Delta {\sf T}_{\sf J}}$	Gate Threshold Voltage Temperature Coefficient	$I_D = 250 \mu A$, Referenced to $25^{\circ}C$		-4		mV/°C
R _{DS(on)}	Static Drain-Source On-Resistance	$\begin{aligned} &V_{GS} = 10 \text{ V}, I_D = 12 \text{ A} \\ &V_{GS} = 10 \text{ V}, I_D = 12 \\ &A, T_J = 125^{\circ}\text{C} \\ &V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A} \end{aligned}$.0009 .0015 .0120	0.012 0.019 0.016	Ω
I _{D(on)}	On-State Drain Current	$V_{GS} = 10 \text{ V}, V_{DS} = 5 \text{ V}$	50			Α
g FS	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 12 \text{ A}$		44		S
Dvnamic (Characteristics					
C _{iss}	Input Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V},$		1700		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		340		pF
C _{rss}	Reverse Transfer Capacitance			140		pF
Switching	Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 15 \text{ V}, I_{D} = 1 \text{ A},$		10	18	ns
t _r	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$		12	22	ns
t _{d(off)}	Turn-Off Delay Time			35	56	ns
t _f	Turn-Off Fall Time			10	18	ns
Q_g	Total Gate Charge	$V_{DS} = 15 \text{ V}, I_D = 12 \text{ A},$		17	23	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 5 V$,		5		nC
Q_{gd}	Gate-Drain Charge			6		nC
Drain-Soເ	rce Diode Characteristics a	nd Maximum Ratings				
I _s	Maximum Continuous Drain-Source				2.3	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 2.3 \text{ A}$ (Note 2)		0.72	1.3	V

R_{BJA} is the sum of the junction-to-case and case-to-ambient resistance where the case thermal reference is defined as the drain tab.
 R_{BJC} is guaranteed by design while R_{BCA} is determined by the user's board design.



Scale 1 : 1 on letter size paper

^{2.} Pulse Test: Pulse Width $\leq 300~\mu\text{s},~\text{Duty Cycle} \leq 2.0\%$

Typical Characteristics

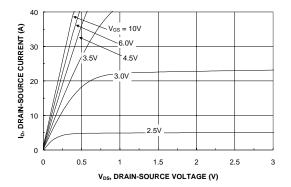
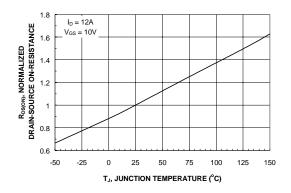


Figure 1. On-Region Characteristics.

Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.



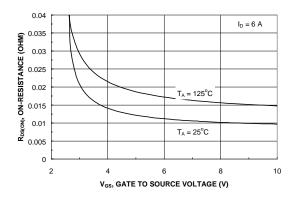
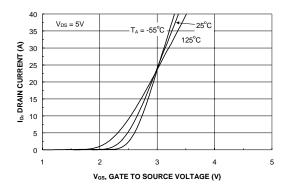


Figure 3. On-Resistance Variation with Temperature.

Figure 4. On-Resistance Variation with Gate-to-Source Voltage.



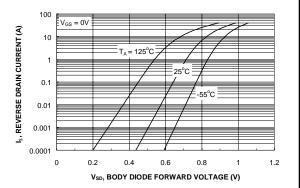
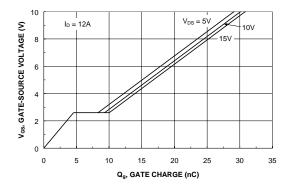


Figure 5. Transfer Characteristics.

Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics (continued)



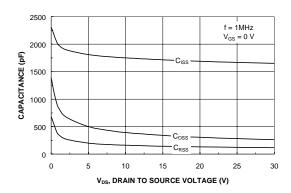
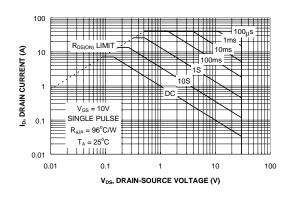


Figure 7. Gate-Charge Characteristics.

Figure 8. Capacitance Characteristics.



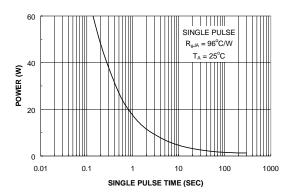


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

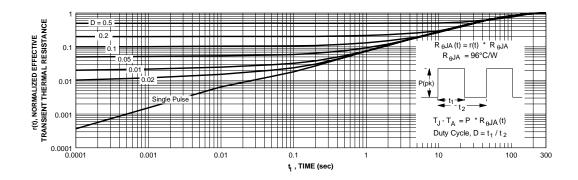


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient themal response will change depending on the circuit board design.

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